

Figure 1. Internal schematic diagram

Features

| Order code | V _{DS} | R _{DS(on)} max | I _D |
|------------|-----------------|-------------------------|----------------|
| STP13N65M2 | 650 V | 0.43Ω | 10A |
| STU13N65M2 | | | |

- Extremely low gate charge
- Excellent output capacitance (C_{oss}) profile
- 100% avalanche tested
- Zener-protected

Applications

- Switching applications

Description

These devices are N-channel Power MOSFETs developed using MDmesh™ M2 technology. Thanks to their strip layout and improved vertical structure, the devices exhibit low on-resistance and optimized switching characteristics, rendering them suitable for the most demanding high efficiency converters.

Table 1. Device summary

| Order code | Marking | Package | Packaging |
|------------|---------|---------|-----------|
| STP13N65M2 | 13N65M2 | TO-220 | Tube |
| STU13N65M2 | | IPAK | |

Contents

| | | |
|----------|-------------------------------------|-----------|
| 1 | Electrical ratings | 3 |
| 2 | Electrical characteristics | 4 |
| 2.1 | Electrical characteristics (curves) | 6 |
| 3 | Test circuits | 9 |
| 4 | Package mechanical data | 10 |
| 4.1 | TO-220, STP13N65M2 | 11 |
| 4.2 | IPAK, STU13N65M2 | 13 |
| 5 | Revision history | 15 |

1 Electrical ratings

Table 2. Absolute maximum ratings

| Symbol | Parameter | Value | Unit |
|----------------|---|-------------|------------------|
| V_{GS} | Gate-source voltage | ± 25 | V |
| I_D | Drain current (continuous) at $T_C = 25^\circ\text{C}$ | 10 | A |
| I_D | Drain current (continuous) at $T_C = 100^\circ\text{C}$ | 6.3 | A |
| $I_{DM}^{(1)}$ | Drain current (pulsed) | 40 | A |
| P_{TOT} | Total dissipation at $T_C = 25^\circ\text{C}$ | 110 | W |
| $dv/dt^{(2)}$ | Peak diode recovery voltage slope | 15 | V/ns |
| $dv/dt^{(3)}$ | MOSFET dv/dt ruggedness | 50 | |
| T_{stg} | Storage temperature | - 55 to 150 | $^\circ\text{C}$ |
| T_j | Max. operating junction temperature | 150 | |

1. Pulse width limited by safe operating area.
2. $I_{SD} \leq 10 \text{ A}$, $di/dt \leq 400 \text{ A}/\mu\text{s}$; V_{DS} peak < $V_{(BR)DSS}$, $V_{DD} = 400 \text{ V}$
3. $V_{DS} \leq 520 \text{ V}$

Table 3. Thermal data

| Symbol | Parameter | Value | | Unit |
|----------------|---|--------|------|---------------------------|
| | | TO-220 | IPAK | |
| $R_{thj-case}$ | Thermal resistance junction-case max | 1.14 | 100 | $^\circ\text{C}/\text{W}$ |
| $R_{thj-amb}$ | Thermal resistance junction-ambient max | | | |

Table 4. Avalanche characteristics

| Symbol | Parameter | Value | Unit |
|----------|---|-------|------|
| I_{AR} | Avalanche current, repetitive or not repetitive (pulse width limited by T_{jmax}) | 1.8 | A |
| E_{AS} | Single pulse avalanche energy (starting $T_j = 25^\circ\text{C}$, $I_D = I_{AR}$; $V_{DD} = 50 \text{ V}$) | 350 | mJ |

2 Electrical characteristics

($T_C = 25^\circ\text{C}$ unless otherwise specified)

Table 5. On /off states

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|-----------------------------|-----------------------------------|---|------|------|----------|---------------|
| $V_{(\text{BR})\text{DSS}}$ | Drain-source breakdown voltage | $V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$ | 650 | | | V |
| I_{DSS} | Zero gate voltage drain current | $V_{GS} = 0 \text{ V}, V_{DS} = 650 \text{ V}$ | | | 1 | μA |
| | | $V_{GS} = 0 \text{ V}, V_{DS} = 650 \text{ V}, T_C = 125^\circ\text{C}$ | | | 100 | μA |
| I_{GSS} | Gate-body leakage current | $V_{DS} = 0 \text{ V}, V_{GS} = \pm 25 \text{ V}$ | | | ± 10 | μA |
| $V_{GS(\text{th})}$ | Gate threshold voltage | $V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$ | 2 | 3 | 4 | V |
| $R_{DS(\text{on})}$ | Static drain-source on-resistance | $V_{GS} = 10 \text{ V}, I_D = 5 \text{ A}$ | | 0.37 | 0.43 | Ω |

Table 6. Dynamic

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|----------------------------|-------------------------------|--|------|-------|------|----------|
| C_{iss} | Input capacitance | $V_{DS} = 100 \text{ V}, f = 1 \text{ MHz}, V_{GS} = 0 \text{ V}$ | - | 590 | - | pF |
| C_{oss} | Output capacitance | | - | 27.5 | - | pF |
| C_{rss} | Reverse transfer capacitance | | - | 1.1 | - | pF |
| $C_{oss \text{ eq}}^{(1)}$ | Equivalent output capacitance | $V_{GS} = 0 \text{ V}, V_{DS} = 0 \text{ to } 520 \text{ V}$ | - | 168.5 | - | pF |
| R_G | Intrinsic gate resistance | $f = 1 \text{ MHz}$ open drain | - | 6.5 | - | Ω |
| Q_g | Total gate charge | $V_{DD} = 520 \text{ V}, I_D = 10 \text{ A}, V_{GS} = 10 \text{ V}$ (see Figure 17) | - | 17 | - | nC |
| Q_{gs} | Gate-source charge | | - | 3.3 | - | nC |
| Q_{gd} | Gate-drain charge | | - | 7 | - | nC |

1. $C_{oss \text{ eq}}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}

Table 7. Switching times

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|---------------------|---------------------|---|------|------|------|------|
| $t_{d(\text{on})}$ | Turn-on delay time | $V_{DD} = 325 \text{ V}, I_D = 5 \text{ A}, R_G = 4.7 \Omega, V_{GS} = 10 \text{ V}$ (see Figure 16 and Figure 21) | - | 11 | - | ns |
| t_r | Rise time | | - | 7.8 | - | ns |
| $t_{d(\text{off})}$ | Turn-off delay time | | - | 38 | - | ns |
| t_f | Fall time | | - | 12 | - | ns |

Table 8. Source drain diode

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|-----------------|-------------------------------|---|------|------|------|---------------|
| I_{SD} | Source-drain current | | - | | 10 | A |
| $I_{SDM}^{(1)}$ | Source-drain current (pulsed) | | - | | 40 | A |
| $V_{SD}^{(2)}$ | Forward on voltage | $V_{GS} = 0 \text{ V}, I_{SD} = 10 \text{ A}$ | - | | 1.6 | V |
| t_{rr} | Reverse recovery time | $I_{SD} = 10 \text{ A}, di/dt = 100 \text{ A}/\mu\text{s}$ $V_{DD} = 60 \text{ V}$ (see <i>Figure 18</i>) | - | 312 | | ns |
| Q_{rr} | Reverse recovery charge | | - | 2.7 | | μC |
| I_{RRM} | Reverse recovery current | | - | 17.5 | | A |
| t_{rr} | Reverse recovery time | $I_{SD} = 10 \text{ A}, di/dt = 100 \text{ A}/\mu\text{s},$ $V_{DD} = 60 \text{ V}, T_j = 150 \text{ }^\circ\text{C}$ (see <i>Figure 18</i>) | - | 464 | | ns |
| Q_{rr} | Reverse recovery charge | | - | 4.1 | | μC |
| I_{RRM} | Reverse recovery current | | - | 17.5 | | A |

1. Pulse width limited by safe operating area.
2. Pulsed: pulse duration = 300 μs , duty cycle 1.5%

2.1 Electrical characteristics (curves)

Figure 2. Safe operating area for TO-220

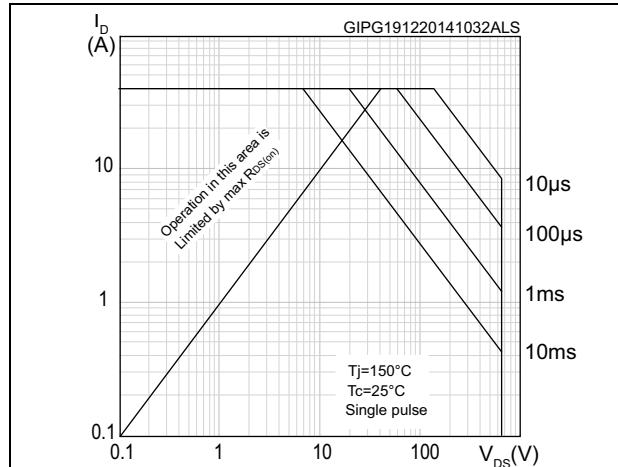


Figure 3. Thermal impedance for TO-220

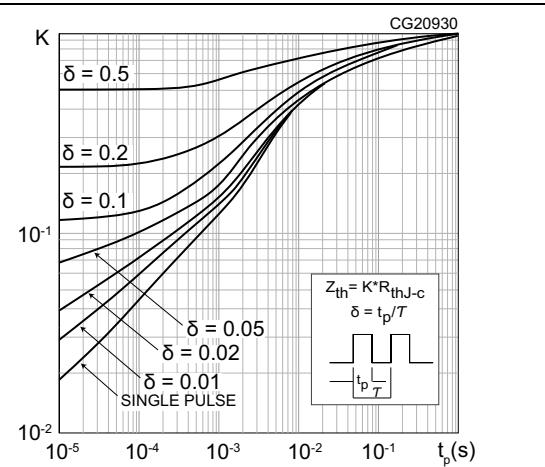


Figure 4. Safe operating area for IPAK

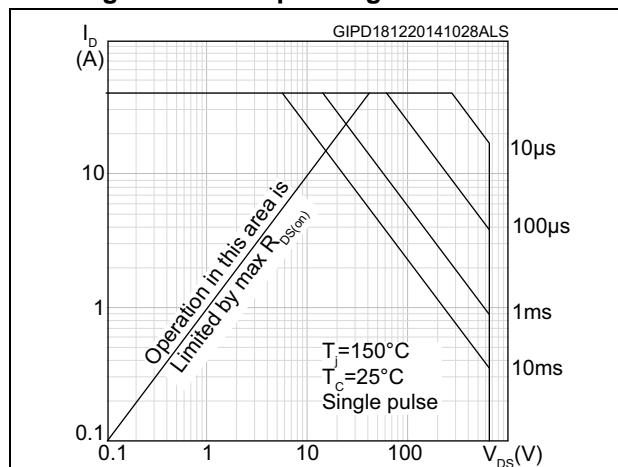


Figure 5. Thermal impedance for IPAK

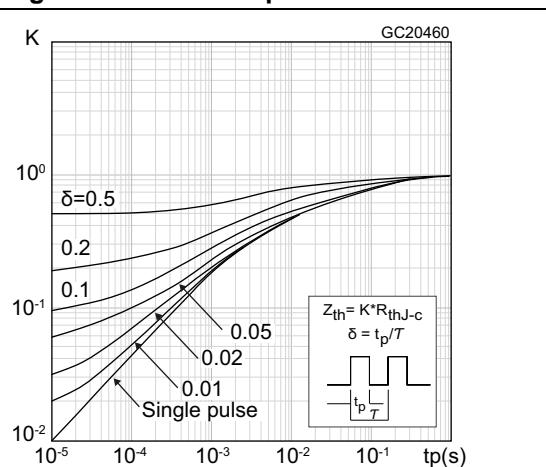


Figure 6. Output characteristics

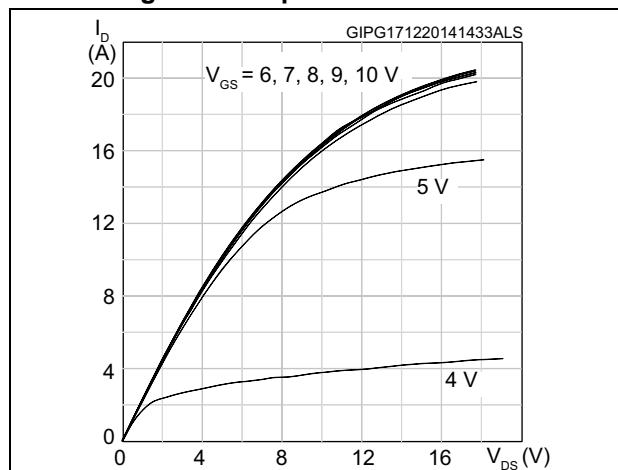


Figure 7. Transfer characteristics

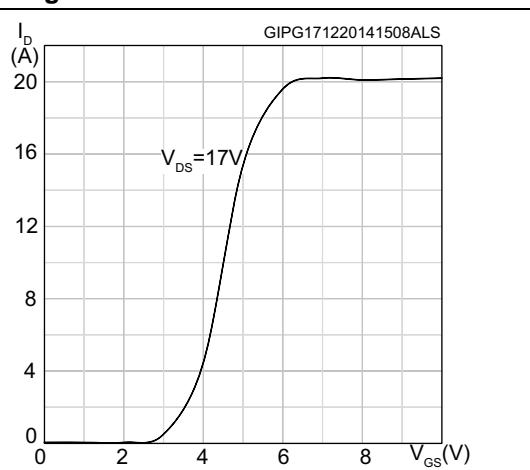


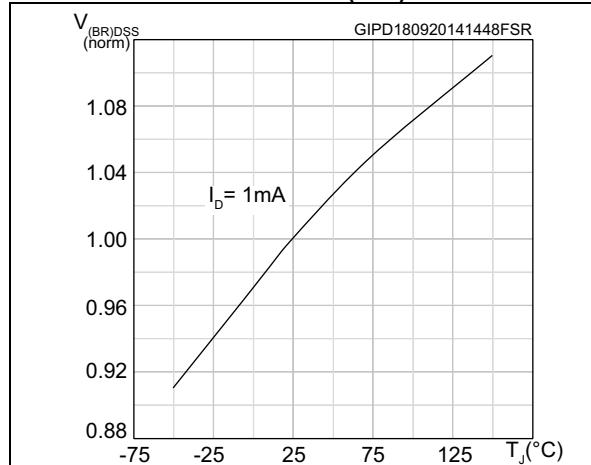
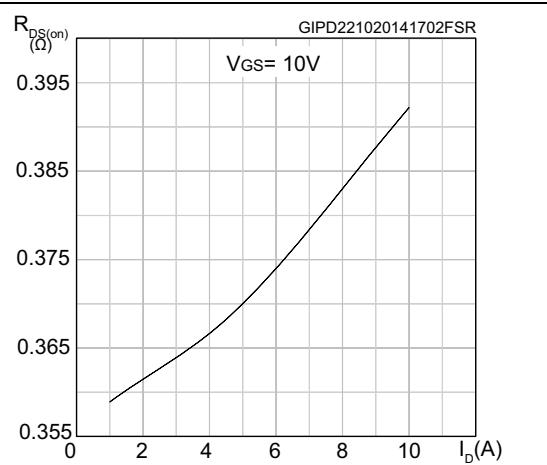
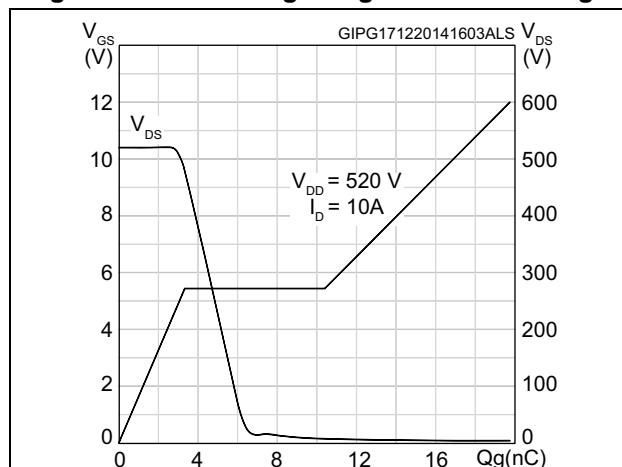
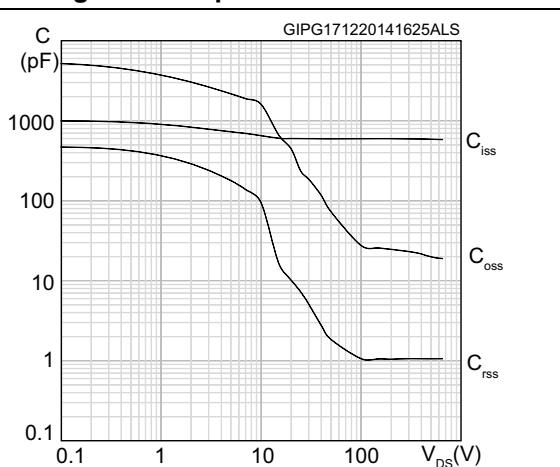
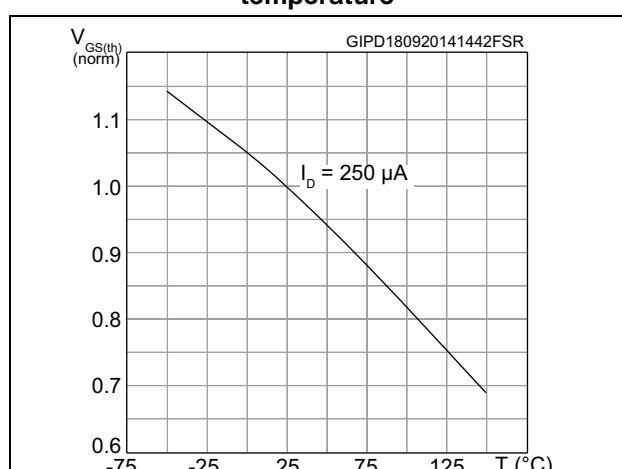
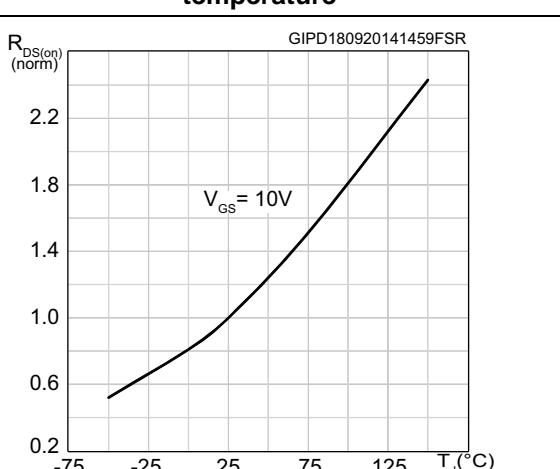
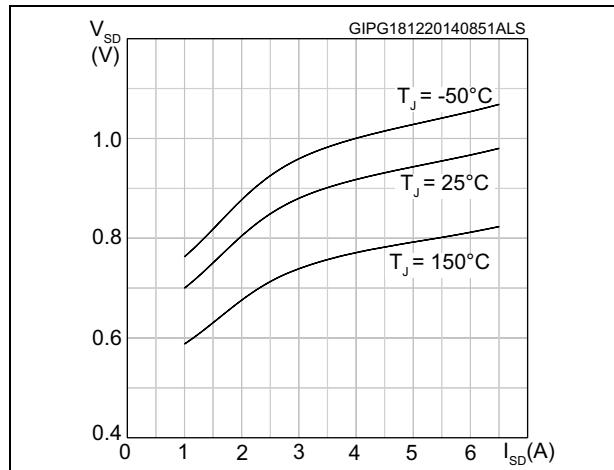
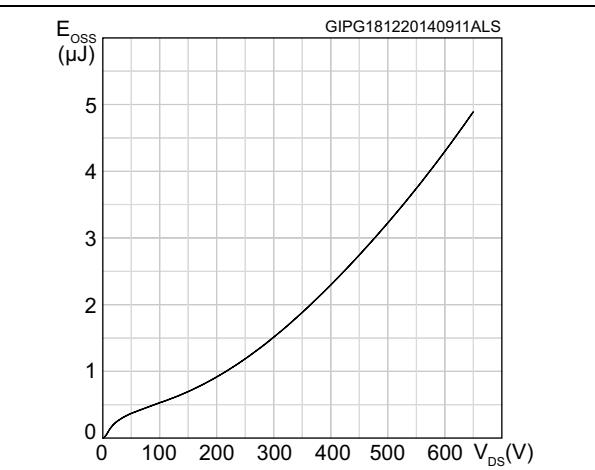
Figure 8. Normalized $V_{BR(DSS)}$ vs temperature**Figure 9. Static drain-source on-resistance****Figure 10. Gate charge vs gate-source voltage****Figure 11. Capacitance variations****Figure 12. Normalized gate threshold voltage vs temperature****Figure 13. Normalized on-resistance vs temperature**

Figure 14. Source-drain diode forward characteristics**Figure 15. Output capacitance stored energy**

3 Test circuits

Figure 16. Switching times test circuit for resistive load

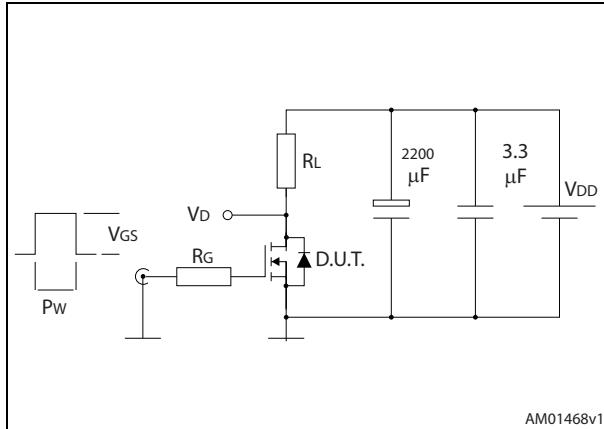


Figure 17. Gate charge test circuit

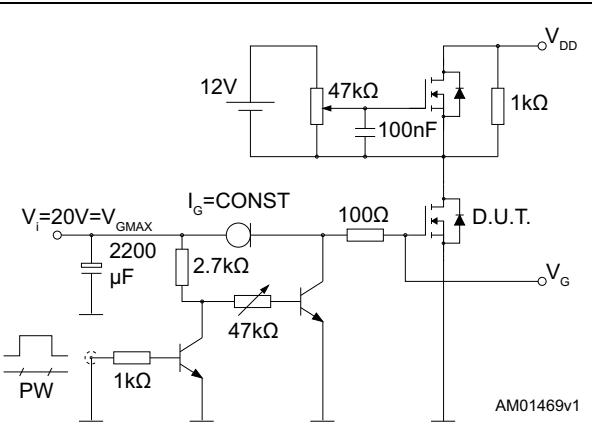


Figure 18. Test circuit for inductive load switching and diode recovery times

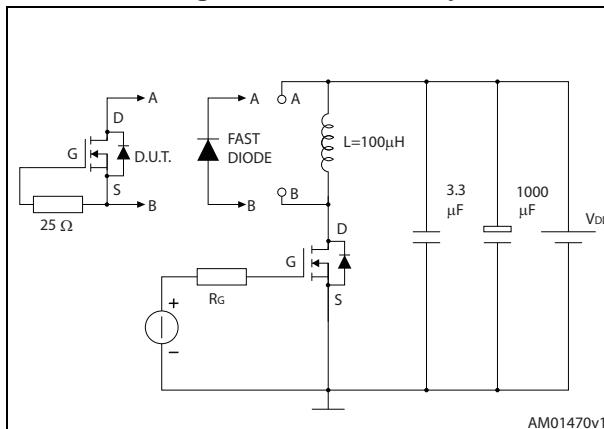


Figure 19. Unclamped inductive load test circuit

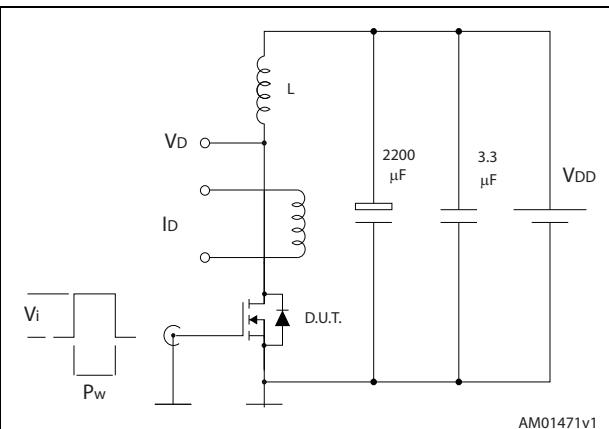


Figure 20. Unclamped inductive waveform

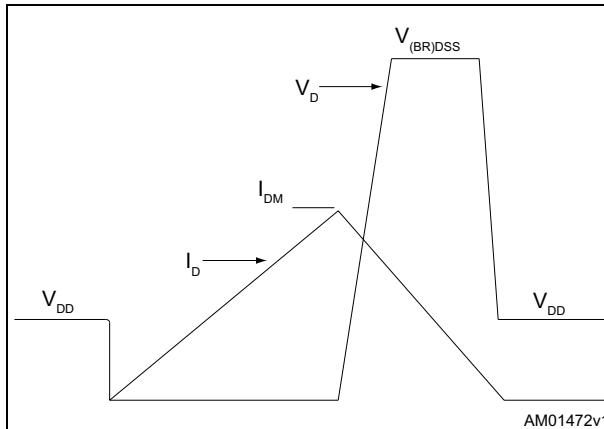
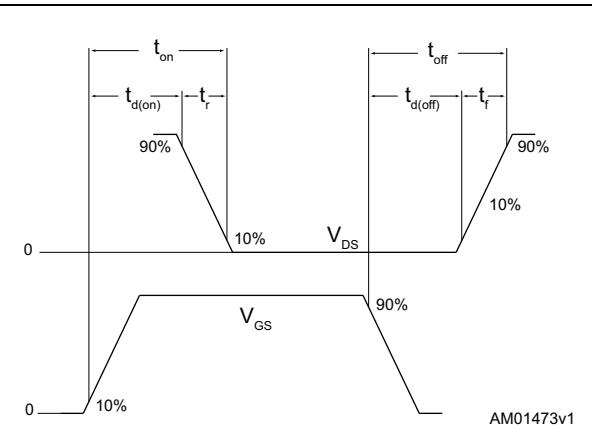


Figure 21. Switching time waveform

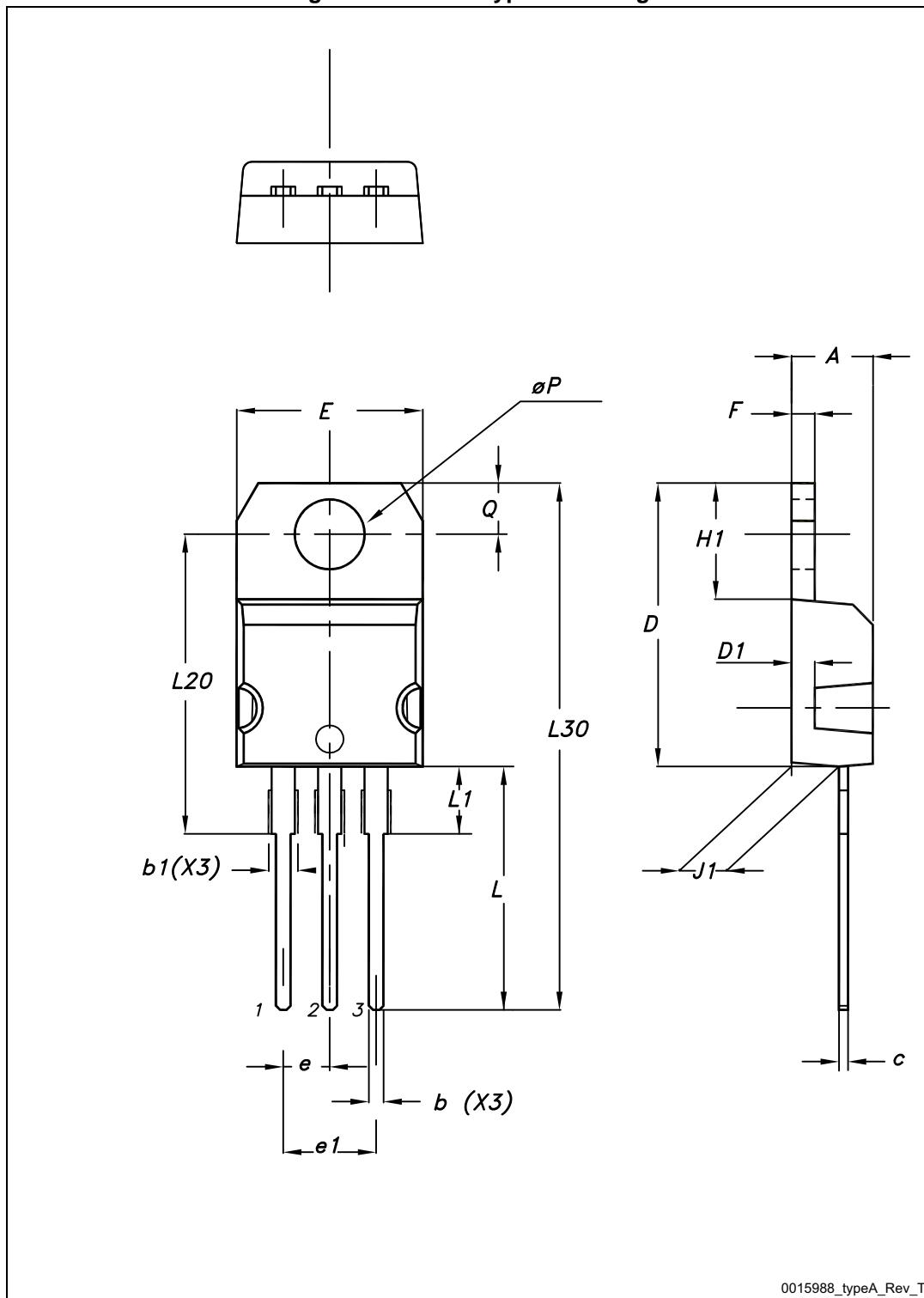


4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com.
ECOPACK® is an ST trademark.

4.1 TO-220, STP13N65M2

Figure 22. TO-220 type A drawing



0015988_typeA_Rev_T

Table 9. TO-220 type A mechanical data

| Dim. | mm | | |
|------|-------|-------|-------|
| | Min. | Typ. | Max. |
| A | 4.40 | | 4.60 |
| b | 0.61 | | 0.88 |
| b1 | 1.14 | | 1.70 |
| c | 0.48 | | 0.70 |
| D | 15.25 | | 15.75 |
| D1 | | 1.27 | |
| E | 10 | | 10.40 |
| e | 2.40 | | 2.70 |
| e1 | 4.95 | | 5.15 |
| F | 1.23 | | 1.32 |
| H1 | 6.20 | | 6.60 |
| J1 | 2.40 | | 2.72 |
| L | 13 | | 14 |
| L1 | 3.50 | | 3.93 |
| L20 | | 16.40 | |
| L30 | | 28.90 | |
| ØP | 3.75 | | 3.85 |
| Q | 2.65 | | 2.95 |

4.2 IPAK, STU13N65M2

Figure 23. IPAK (TO-251) drawing

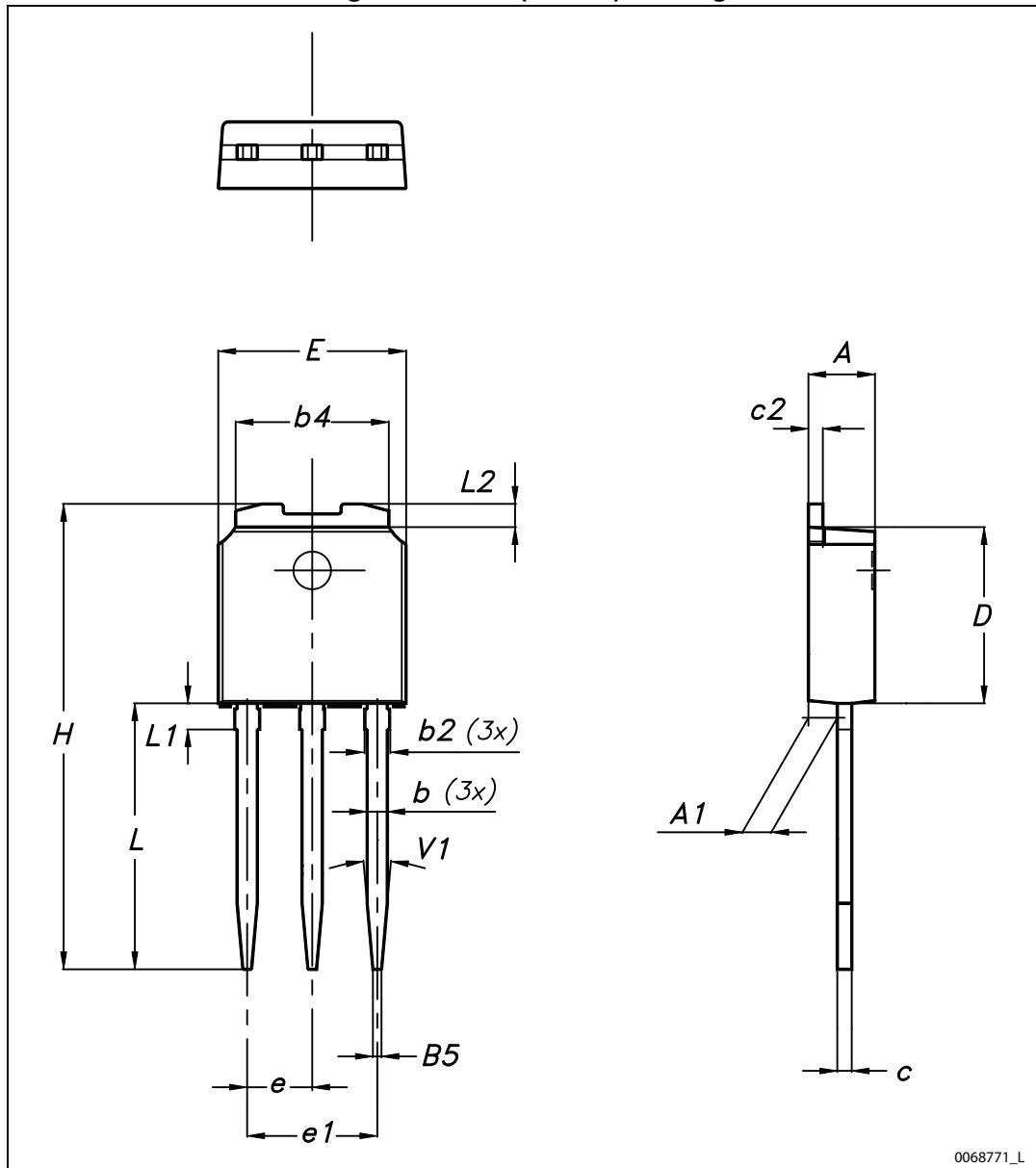


Table 10. IPAK (TO-251) mechanical data

| DIM | mm. | | |
|-----|------|-------|------|
| | min. | typ. | max. |
| A | 2.20 | | 2.40 |
| A1 | 0.90 | | 1.10 |
| b | 0.64 | | 0.90 |
| b2 | | | 0.95 |
| b4 | 5.20 | | 5.40 |
| B5 | | 0.30 | |
| c | 0.45 | | 0.60 |
| c2 | 0.48 | | 0.60 |
| D | 6.00 | | 6.20 |
| E | 6.40 | | 6.60 |
| e | | 2.28 | |
| e1 | 4.40 | | 4.60 |
| H | | 16.10 | |
| L | 9.00 | | 9.40 |
| L1 | 0.80 | | 1.20 |
| L2 | | 0.80 | 1.00 |
| V1 | | 10° | |

5 Revision history

Table 11. Document revision history

| Date | Revision | Changes |
|-------------|----------|----------------|
| 19-Dec-2014 | 1 | First release. |

IMPORTANT NOTICE – PLEASE READ CAREFULLY

STMicroelectronics NV and its subsidiaries ("ST") reserve the right to make changes, corrections, enhancements, modifications, and improvements to ST products and/or to this document at any time without notice. Purchasers should obtain the latest relevant information on ST products before placing orders. ST products are sold pursuant to ST's terms and conditions of sale in place at the time of order acknowledgement.

Purchasers are solely responsible for the choice, selection, and use of ST products and ST assumes no liability for application assistance or the design of Purchasers' products.

No license, express or implied, to any intellectual property right is granted by ST herein.

Resale of ST products with provisions different from the information set forth herein shall void any warranty granted by ST for such product.

ST and the ST logo are trademarks of ST. All other product or service names are the property of their respective owners.

Information in this document supersedes and replaces information previously supplied in any prior versions of this document.

© 2014 STMicroelectronics – All rights reserved